## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | SERIZAWA ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H.	US-			-
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003009994 A	01-2003	Japan	YAMASHITA et al.	
	0	JP 2003128900 A	05-2003	Japan	TAKAGI, JUN	
	Р	JP 2003096321 A	04-2003	Japan	INAO et al.	•
	Q	JP 2002356562 A	12-2002	Japan	INAO et al.	
	R	JP 2000141524 A	05-2000	Japan	HETA et al.	
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.